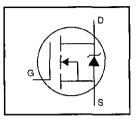
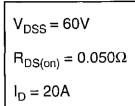
# **IRFIZ34G**

#### HEXFET® Power MOSFET

- Isolated Package
- High Voltage Isolation= 2.5KVRMS ®
- Sink to Lead Creepage Dist.= 4.8mm
- 175°C Operating Temperature
- Dynamic dv/dt Rating
- Low Thermal Resistance

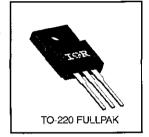




#### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.



#### Absolute Maximum Ratings

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, VGS @ 10 V	20		
ID @ TC = 100°C	Continuous Drain Current, VGS @ 10 V	14	Α	
Ірм	Pulsed Drain Current ①	80		
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	42	W	
	Linear Derating Factor	0.28	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V	
Eas	Single Pulse Avalanche Energy ②	300	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +175	°C	
<u>-</u> -	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)		

#### Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
Reuc	Junction-to-Case			3.6	°C/W
Reja	Junction-to-Ambient	_		65	0/11

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### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	60	<u> </u>	_	٧	V <sub>GS</sub> =0V, I <sub>D</sub> = 250μA
ΔV(8R)DSS/ΔTJ	Breakdown Voltage Temp. Coefficient	_	0.065	_	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
Ros(on)	Static Drain-to-Source On-Resistance	-		0.050	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =12A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	_	4.0	ν	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 250μA
9fs	Forward Transconductance	9.2	_		S	V <sub>DS</sub> =25V, I <sub>D</sub> =12A ④
	Drain-to-Source Leakage Current		_	25	μА	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V
loss	Drain-to-Source Leakage Current	_	_ !	250	μA	V <sub>DS</sub> =48V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C
Igss	Gate-to-Source Forward Leakage		_	100	nA	V <sub>GS</sub> =20V
IGSS	Gate-to-Source Reverse Leakage	-	ļ	-100	ш	V <sub>GS</sub> =-20V
Q <sub>9</sub>	Total Gate Charge	<u> </u>		46		ID=30A
Q <sub>gs</sub>	Gate-to-Source Charge	<u> </u>	_	11	пС	V <sub>DS</sub> =48V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	<u> </u>		22		V <sub>GS</sub> =10V See Fig. 6 and 13 @
t <sub>d(on)</sub>	Turn-On Detay Time	<u> </u>	13			V <sub>DD</sub> =30V
tr	Rise Time	<u> </u>	100		ns	ID=30A
t <sub>d(off)</sub>	Turn-Off Delay Time		29		1.0	R <sub>G</sub> =12Ω
t <sub>f</sub>	Fall Time	-	52	_		R <sub>D</sub> =1.0Ω See Figure 10 €
LD	Internal Drain Inductance		4.5		nΗ	Between lead, 6 mm (0.25in.)
Ls	Internal Source Inductance	-	7.5		111.3	from package and center of die contact
Ciss	Input Capacitance		1200			V <sub>GS</sub> =0V
Coss	Output Capacitance		600		рF	V <sub>DS</sub> = 25V
Crss	Reverse Transfer Capacitance		100			f=1.0MHz See Figure 5
С	Drain to Sink Capacitance	_	12		рF	f=1.0MHz

## Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
s	Continuous Source Current (Body Diode)	-	_	20		MOSFET symbol showing the
SM	Pulsed Source Current (Body Diode) ①		_	80	A	integral reverse p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.6	V	TJ=25°C, Is=20A, VGS=0V &
trr	Reverse Recovery Time		120	230	пѕ	T <sub>J</sub> =25°C, I <sub>F</sub> =30A
Qrr	Reverse Recovery Charge		0.70	1.4	μC	di/dt=100A/μs ④
ton	Forward Turn-On Time	Intrinsion	Intrinsic turn-on time is neglegible (turn-on is dominated by Ls+Lp)			

#### Notes:

- Repetitive rating; pulse width limited by max, junction temperature (See Figure 11)
- ③ IsD≤30A, di/dt≤200A/μs, VDD≤V(BR)DSs, TJ≤175°C
- 5 t=60s, f=60Hz

- ② VDD=25V, starting T<sub>J</sub>=25°C, L=875μH RG=25Ω, I<sub>AS</sub>=20A (See Figure 12)
- ⊕ Pulse width ≤ 300 μs; duty cycle ≤2%.

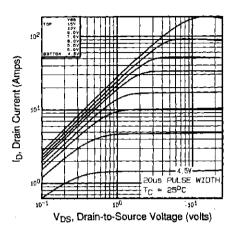


Fig 1. Typical Output Characteristics, T<sub>C</sub>=25°C

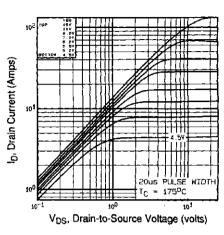


Fig 2. Typical Output Characteristics, T<sub>C</sub>=175°C

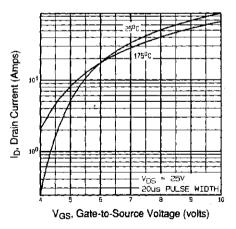


Fig 3. Typical Transfer Characteristics

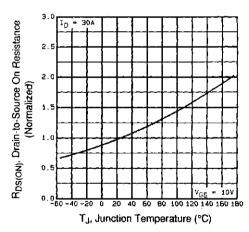


Fig 4. Normalized On-Resistance Vs. Temperature

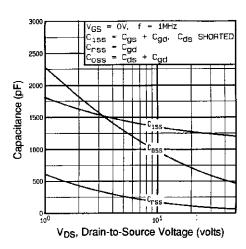


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

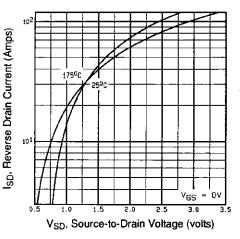


Fig 7. Typical Source-Drain Diode Forward Voltage

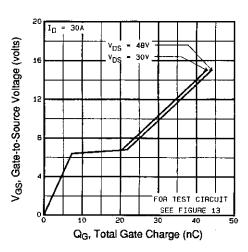


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

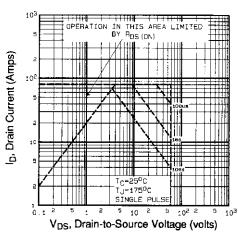


Fig 8. Maximum Safe Operating Area

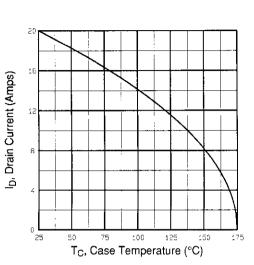


Fig 9. Maximum Drain Current Vs. Case Temperature

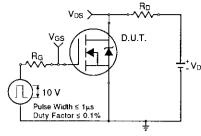


Fig 10a. Switching Time Test Circuit

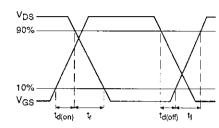


Fig 10b. Switching Time Waveforms

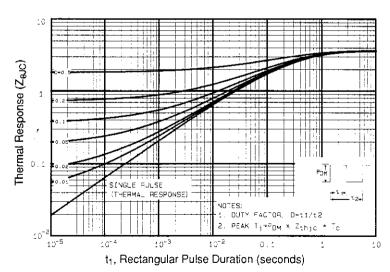


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

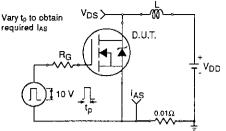


Fig 12a. Unclamped Inductive Test Circuit

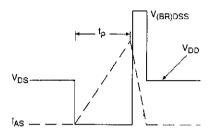


Fig 12b. Unclamped Inductive Waveforms

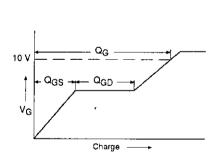


Fig 13a. Basic Gate Charge Waveform

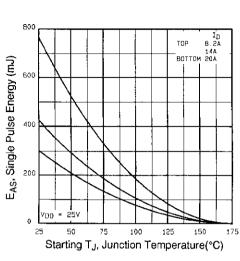


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

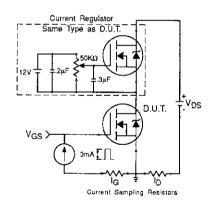


Fig 13b. Gate Charge Test Circuit

Appendix A: Figure 14, Peak Diode Recovery dv/dt Test Circuit - See page 1505

Appendix B: Package Outline Mechanical Drawing - See page 1510

Appendix C: Part Marking Information - See page 1517

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